

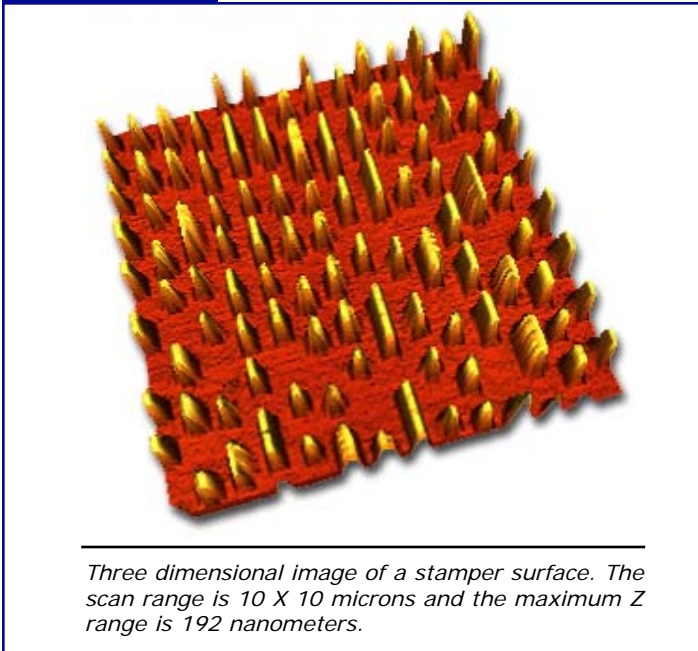
## Atomic Force Microscopy for DVD Analysis:

Directly measuring the topography of bits on masters and replicas with an Atomic Force Microscope (AFM) is useful for quality control and process development. Parameters that are routinely measured with an AFM include:

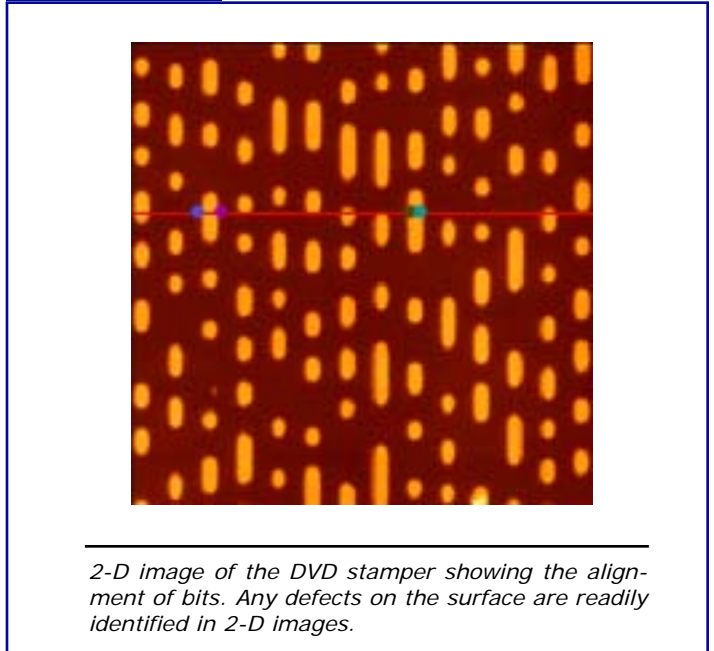
- Track Pitch
- Bit Width - Top and bottom
- Bit Length - Top and bottom
- Bit Angle - All sides
- Bit Height

Additionally, an AFM is very helpful for visualizing defects on the surface of masters and DISCs.

**Figure 1**



**Figure 2**



**Figure 3**

